



A Product Line of Diodes Incorporated

DMC4028SSD

#### 40V COMPLEMENTARY DUAL ENHANCEMENT MODE MOSFET

## **Product Summary**

Device	V <sub>(BR)DSS</sub>	R <sub>DS(on)</sub> Max	I <sub>D</sub> T <sub>A</sub> = +25°C	
Q1	40V	28mΩ @ V <sub>GS</sub> = 10V	7.2A	
QT	40 V	40 V	49mΩ @ V <sub>GS</sub> = 4.5V	5.4A
Q2	-40V	50mΩ @ V <sub>GS</sub> = -10V	-5.2A	
QZ	-40 V	79mΩ @ V <sub>GS</sub> = -4.5V	-4.7A	

## Description

This MOSFET has been designed to minimize the on-state resistance and yet maintain superior switching performance, making it ideal for high efficiency power management applications.

## Applications

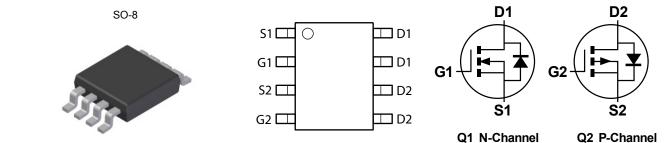
- Motor Control
- Backlighting
- DC-DC Converters
- Power Management Functions

## Features and Benefits

- Low On-Resistance
- Fast Switching Speed
- Totally Lead-Free & Fully RoHS compliant (Notes 1 & 2)
- Halogen and Antimony Free. "Green" Device (Note 3)
- Qualified to AEC-Q101 Standards for High Reliability

## **Mechanical Data**

- Case: SO-8
- Case Material: Molded Plastic, "Green" Molding Compound. UL Flammability Classification Rating 94V-0
- Moisture Sensitivity: Level 1 per J-STD-020
- Terminals Connections: See diagram below
- Terminals: Finish Matte Tin annealed over Copper lead frame. Solderable per MIL-STD-202, Method 208 (3)
- Weight: 0.074 grams (approximate)



Top View

Equivalent Circuit

#### Ordering Information (Note 4)

Top View

Part Number	Compliance	Case	Packaging
DMC4028SSD-13	Standard	SO-8	2500 / Tape & Reel
DMC4028SSDQ-13	Automotive	SO-8	2500 / Tape & Reel

Notes:

No purposely added lead. Fully EU Directive 2002/95/EC (RoHS) & 2011/65/EU (RoHS 2) compliant.
See http://www.diodes.com/quality/lead\_free.html for more information about Diodes Incorporated's definitions of Halogen- and Antimony-free, "Green"

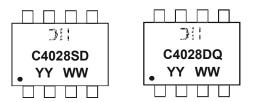
and Lead-free.

3. Halogen- and Antimony-free "Green" products are defined as those which contain <900ppm bromine, <900ppm chlorine (<1500ppm total Br + Cl) and <1000ppm antimony compounds.

III = Manufacturer's Marking

4. For packaging details, go to our website at http"//www.diodes.com/products/packages.html.

## Marking Information



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DMC4028SSD

#### Maximum Ratings (@T<sub>A</sub> = +25°C, unless otherwise specified.)

Characteristic			Symbol	N-Channel - Q1	P-Channel - Q2	Units
Drain-Source Voltage		V <sub>DSS</sub>	40	-40	V	
Gate-Source Voltage		(Note 5)	V <sub>GSS</sub>	±20	±20	V
Continuous Drain Current V <sub>GS</sub> = 10V		(Notes 7 & 9)		7.2	5.2	A
	V <sub>GS</sub> = 10V	T <sub>A</sub> = 70°C (Notes 7 & 9)	ID	5.5	4.2	
		(Notes 6 & 9)		5.4	4	
		(Notes 6 & 10)		6.5	4.8	
Pulsed Drain Current	V <sub>GS</sub> = 10V	(Notes 7 & 9)	I <sub>DM</sub>	27.3	20.4	А
Continuous Source Current (Body diode)		(Notes 7 & 9)	Is	3.35	3.15	А
Pulsed Source Current (Body diode)		(Notes 8 & 9)	I <sub>SM</sub>	27.3	20.4	А

#### Thermal Characteristics (@T<sub>A</sub> = +25°C, unless otherwise specified.)

Characteristic	Symbol	ool N-Channel - Q1 P-Channel - Q		Unit	
	(Notes 6 & 9)		1.	W mW/°C	
Power Dissipation Linear Derating Factor	(Notes 6 & 10)	PD	1.8 14.3		
	(Notes 7 & 9)		2. 17		
	(Notes 6 & 9)		1(	°C/W	
Thermal Resistance, Junction to Ambient	(Notes 6 & 10)	R <sub>0JA</sub>	7		
	(Notes 7 & 9)		58		
Thermal Resistance, Junction to Lead	(Notes 9 & 11)	R <sub>θJL</sub>	53	53	
Operating and Storage Temperature Range		T <sub>J,</sub> T <sub>STG</sub>	-55 to	+150	°C

Notes: 5. AEC-Q101 V<sub>GS</sub> maximum is  $\pm$ 16V.

6. For a device surface mounted on 25mm x 25mm x 1.6mm FR4 PCB with high coverage of single sided 1oz copper, in still air conditions; the device is measured when operating in a steady-state condition. 7. Same as note (5), except the device is measured at t  $\leq$  10 sec. 8. Same as note (5), except the device is pulsed with D= 0.02 and pulse width 300 µs. The pulse current is limited by the maximum junction temperature.

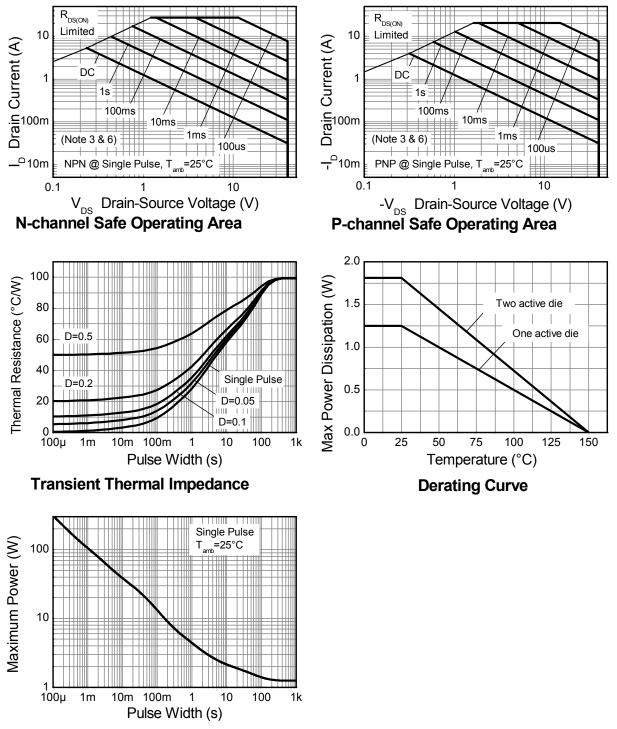
9. For a dual device with one active die.

10. For a device with two active die running at equal power.

11. Thermal resistance from junction to solder-point (at the end of the drain lead).

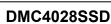


# Thermal Characteristics



Pulse Power Dissipation





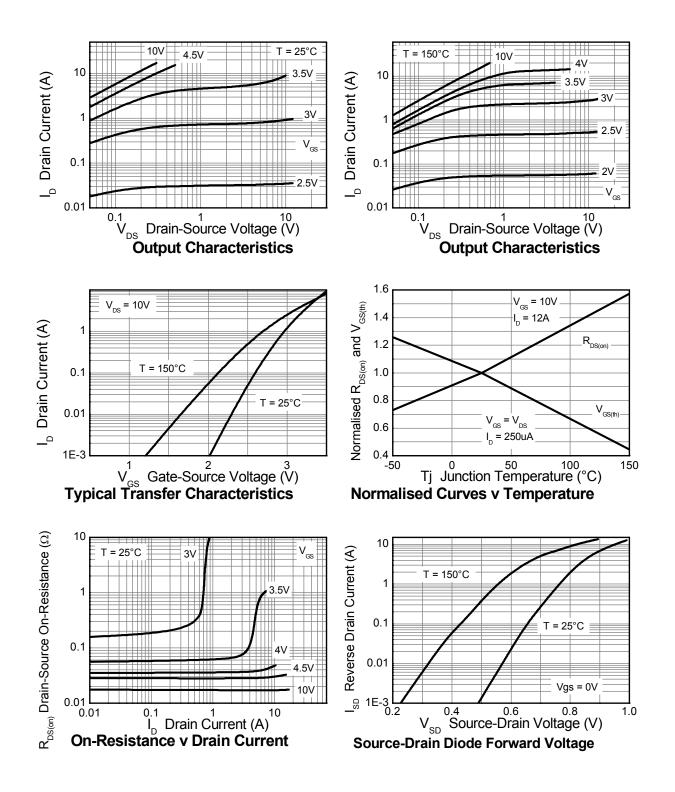
Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition	
OFF CHARACTERISTICS							
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	40	—	_	V	I <sub>D</sub> = 250µA, V <sub>GS</sub> = 0V	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>		—	0.5	μA	V <sub>DS</sub> = 40V, V <sub>GS</sub> = 0V	
Gate-Source Leakage	I <sub>GSS</sub>		—	±100	nA	$V_{GS}$ = ±20V, $V_{DS}$ = 0V	
ON CHARACTERISTICS							
Gate Threshold Voltage	V <sub>GS(th)</sub>	1.0	—	3.0	V	$I_{D} = 250 \mu A, V_{D}$	s = V <sub>GS</sub>
Static Drain-Source On-Resistance (Note 12)	<b>D</b>		0.018	0.028	Ω	V <sub>GS</sub> = 10V, I <sub>D</sub> = 6A V <sub>GS</sub> = 4.5V, I <sub>D</sub> = 5A	
	R <sub>DS (ON)</sub>		0.033	0.049	12		
Forward Transconductance (Notes 12 & 13)	<b>g</b> fs		22.8		S	V <sub>DS</sub> = 15V, I <sub>D</sub> = 6A	
Diode Forward Voltage (Note 12)	V <sub>SD</sub>	_	0.845	1.1	V	$I_{\rm S}$ = 6A, $V_{\rm GS}$ = 0V	
Reverse recovery time (Note 13)	t <sub>rr</sub>		135	_	ns	-I <sub>S</sub> = 6A, di/dt = 100A/μs	
Reverse recovery charge (Note 13)	Qrr	_	799	_	nC		
DYNAMIC CHARACTERISTICS (Note 13)							
Input Capacitance	C <sub>iss</sub>		604	_	pF	V <sub>DS</sub> = 20V, V <sub>GS</sub> = 0V f = 1MHz	
Output Capacitance	C <sub>oss</sub>		106	_	pF		
Reverse Transfer Capacitance	C <sub>rss</sub>	_	59.6	_	pF	1 - 110112	
Total Gate Charge (Note 14)	Qg	_	6.5	_	nC	V <sub>GS</sub> = 4.5V	
Total Gate Charge (Note 14)	Qg	_	12.9	_	nC		V <sub>DS</sub> = 20V
Gate-Source Charge (Note 14)	Q <sub>gs</sub>	_	2.3	_	nC	$V_{GS} = 10V$ $I_D = 6A$	
Gate-Drain Charge (Note 14)	Q <sub>gd</sub>		3.6	_	nC		
Turn-On Delay Time (Note 14)	t <sub>D(on)</sub>		4.2	_	ns	$V_{DD}$ = 20V, $V_{GS}$ = 10V $I_D$ = 6A, $R_G \cong 6.0\Omega$	
Turn-On Rise Time (Note 14)	tr		12.4	_	ns		
Turn-Off Delay Time (Note 14)	t <sub>D(off)</sub>		13.8	_	ns		
Turn-Off Fall Time (Note 14)	t <sub>f</sub>		10.7	_	ns		

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12. Measured under pulsed conditions. Pulse width  $\leq$  300 $\mu$ s; duty cycle  $\leq$  2% 13. For design aid only, not subject to production testing. 14. Switching characteristics are independent of operating junction temperatures. Notes:

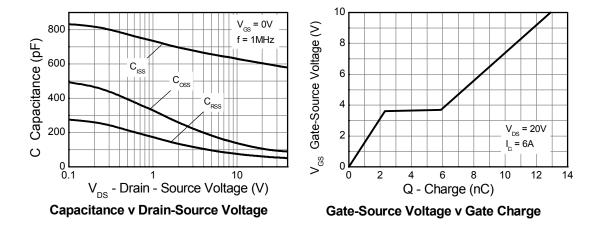


# **Typical Characteristics – Q1 N-Channel**

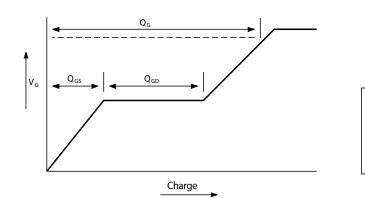




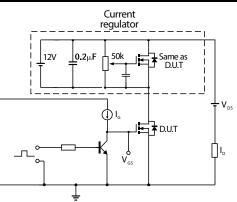
# Typical Characteristics – Q1 N-Channel - (cont.)



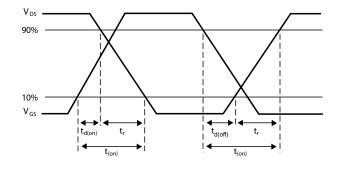
## Test Circuits – Q1 N-Channel



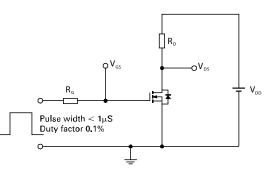
Basic gate charge waveform



Gate charge test circuit



Switching time waveforms



Switching time test circuit





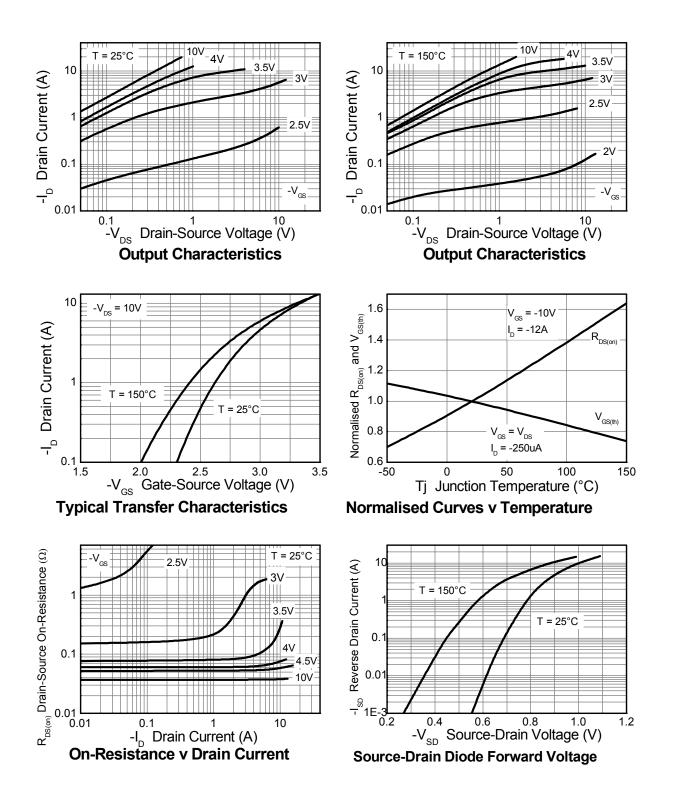
Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition	
OFF CHARACTERISTICS							
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	-40	—	—	V	I <sub>D</sub> = -250 μA, V <sub>GS</sub> = 0V	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	_	—	-0.5	μA	V <sub>DS</sub> = -40V, V <sub>GS</sub> = 0V	
Gate-Source Leakage	I <sub>GSS</sub>	_	—	±100	nA	$V_{GS}$ = ±20V, $V_{DS}$ = 0V	
ON CHARACTERISTICS							
Gate Threshold Voltage	V <sub>GS(th)</sub>	-1.0	-	-3.0	V	I <sub>D</sub> = -250 μA, V	<sub>DS</sub> = V <sub>GS</sub>
Static Drain-Source On-Resistance (Note 12)	D		0.039	0.050	0	$Ω = \frac{V_{GS} = -10V, I_D = -6A}{V_{GS} = -4.5V, I_D = -5A}$	
	R <sub>DS(ON)</sub>		0.060	0.079	12		
Forward Transconductance (Notes 12 & 13)	<b>g</b> fs	—	16.6	—	S	V <sub>DS</sub> = -15V, I <sub>D</sub> = -6A	
Diode Forward Voltage (Note 13)	V <sub>SD</sub>	_	-0.865	-1.1	V	$I_{\rm S}$ = -6A, $V_{\rm GS}$ = 0V	
Reverse Recovery Time (Note 13)	t <sub>rr</sub>	_	138	_	ns	−I <sub>S</sub> = -6A, di/dt = 100A/µs	
Reverse Recovery Charge (Note 13)	Q <sub>rr</sub>	_	841	_	nC		
DYNAMIC CHARACTERISTICS (Note 13)							
Input Capacitance	C <sub>iss</sub>	_	674	—	pF	V <sub>DS</sub> = -20V, V <sub>GS</sub> = 0V f = 1MHz	
Output Capacitance	C <sub>oss</sub>	_	115	—	pF		
Reverse Transfer Capacitance	C <sub>rss</sub>	_	67.7	—	pF		
Total Gate Charge (Note 14)	Qg	_	7.0	—	nC	V <sub>GS</sub> = -4.5V	
Total Gate Charge (Note 14)	Qg	—	14	—	nC		V <sub>DS</sub> = -20V
Gate-Source Charge (Note 14)	Q <sub>gs</sub>	—	2.2	—	nC	V <sub>GS</sub> = -10V	I <sub>D</sub> = -6A
Gate-Drain Charge (Note 14)	Q <sub>gd</sub>	—	3.7	—	nC	1	
Turn-On Delay Time (Note 14)	t <sub>D(on)</sub>	—	2.3	—	ns	1	
Turn-On Rise Time (Note 14)	tr	_	14.1	—	ns	V <sub>DD</sub> = -20V, V <sub>G</sub>	<sub>S</sub> = -10V
Turn-Off Delay Time (Note 14)	t <sub>D(off)</sub>	_	25.1	—	ns	$I_D = -6A, R_G \cong 6.0\Omega$	
Turn-Off Fall Time (Note 14)	t <sub>f</sub>	_	14.3	—	ns		

#### Electrical Characteristics O2 P Channel

12. Measured under pulsed conditions. Pulse width  $\leq$  300µs; duty cycle  $\leq$  2% 13. For design aid only, not subject to production testing. 14. Switching characteristics are independent of operating junction temperatures. Notes:

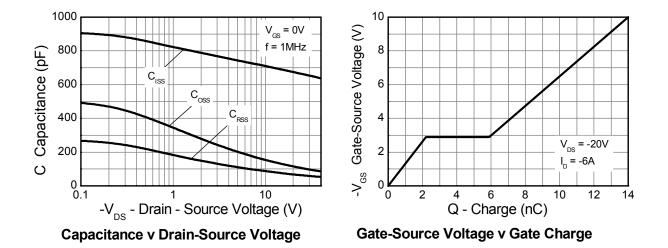


# **Typical Characteristics – Q2 P-Channel**

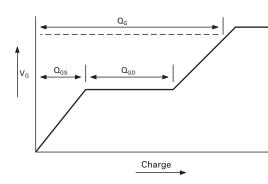




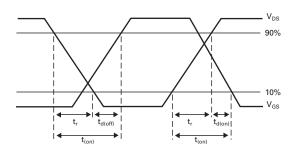
## Typical Characteristics – Q2 P-Channel – (cont.)



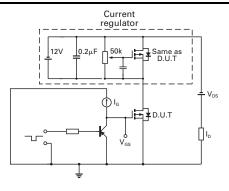
## Test Circuits – Q2 P-Channel



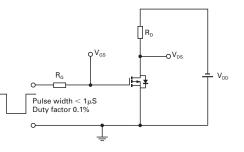
Basic gate charge waveform



Switching time waveforms



#### Gate charge test circuit

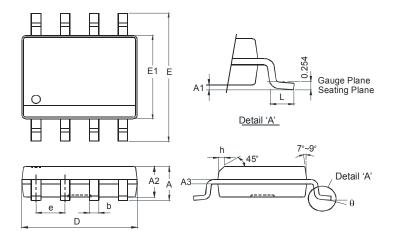


Switching time test circuit



## **Package Outline Dimensions**

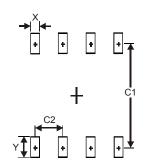
Please see AP02002 at http://www.diodes.com/datasheets/ap02002.pdf for latest version.



	SO-8						
Dim	Min	Max					
Α	-	1.75					
A1	0.10	0.20					
A2	1.30	1.50					
A3	0.15	0.25					
b	0.3	0.5					
D	4.85	4.95					
E	5.90	6.10					
E1	3.85	3.95					
е	1.27	Тур					
h	-	0.35					
L	0.62	0.82					
θ	0°	8°					
All Di	All Dimensions in mm						

## Suggested Pad Layout

Please see AP02001 at http://www.diodes.com/datasheets/ap02001.pdf for the latest version.



Dimensions	Value (in mm)
Х	0.60
Y	1.55
C1	5.4
C2	1.27



DMC4028SSD

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